

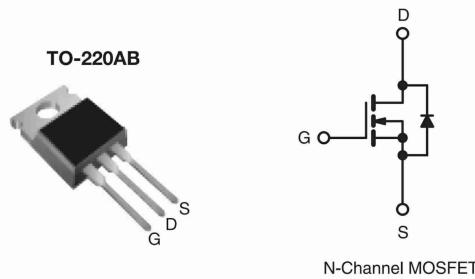
AOT22N50L-VB Datasheet

550V Single-N Planar TO220 MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	550	
$R_{DS(on)}$ at 25 °C (Ω)	$V_{GS} = 10$ V	0.2
Q_g max. (nC)	170	
Q_{gs} (nC)	14	
Q_{gd} (nC)	28	
Configuration	Single	

FEATURES

- Optimal Design
 - Low Area Specific On-Resistance
 - Low Input Capacitance (C_{iss})
 - Reduced Capacitive Switching Losses
 - High Body Diode Ruggedness
 - Avalanche Energy Rated (UIS)
- Optimal Efficiency and Operation
 - Low Cost
 - Simple Gate Drive Circuitry
 - Low Figure-of-Merit (FOM): $R_{on} \times Q_g$
 - Fast Switching



APPLICATIONS

- Consumer Electronics
 - Displays (LCD or Plasma TV)
- Server and Telecom Power Supplies
 - SMPS
- Industrial
 - Welding
 - Induction Heating
 - Motor Drives
- Battery Chargers
- SMPS
 - Power Factor Correction (PFC)

ABSOLUTE MAXIMUM RATINGS ($T_C = 25$ °C, unless otherwise noted)			
PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V_{DS}	550	V
Gate-Source Voltage		± 20	
Gate-Source Voltage AC ($f > 1$ Hz)		30	
Continuous Drain Current ($T_J = 150$ °C)	I_D	20	A
V_{GS} at 10 V		13	
Pulsed Drain Current ^a	I_{DM}	62	W/°C
Linear Derating Factor		2.2	
Single Pulse Avalanche Energy ^b	E_{AS}	281	mJ
Maximum Power Dissipation	P_D	278	W
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to + 150	°C
Drain-Source Voltage Slope	dV/dt	24	V/ns
Reverse Diode dV/dt ^d		0.36	
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^c	°C

Notes

- Repetitive rating; pulse width limited by maximum junction temperature.
- $V_{DD} = 50$ V, starting $T_J = 25$ °C, $L = 10$ mH, $R_g = 25$ Ω, $I_{AS} = 7.5$ A.
- 1.6 mm from case.
- $I_{SD} \leq I_D$, starting $T_J = 25$ °C.

THERMAL RESISTANCE RATINGS

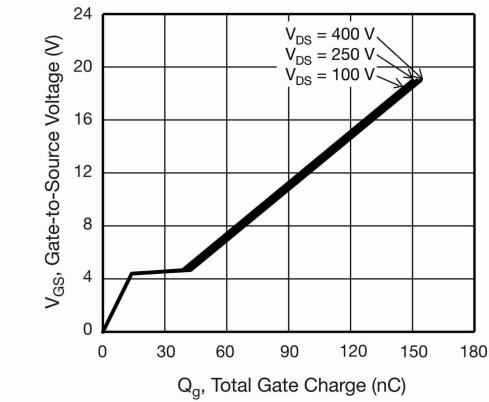
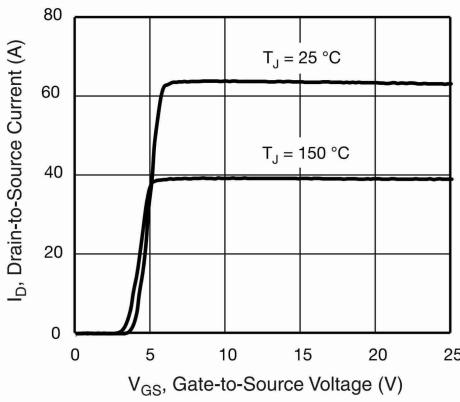
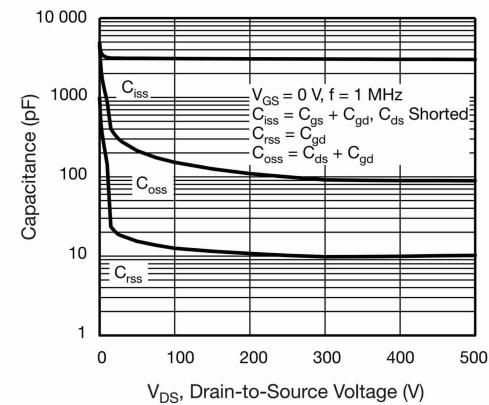
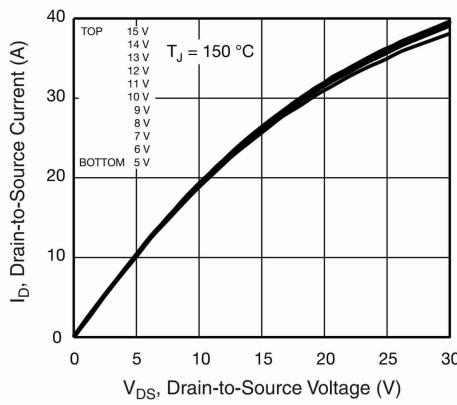
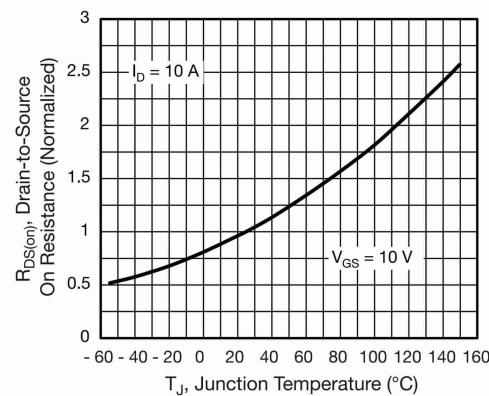
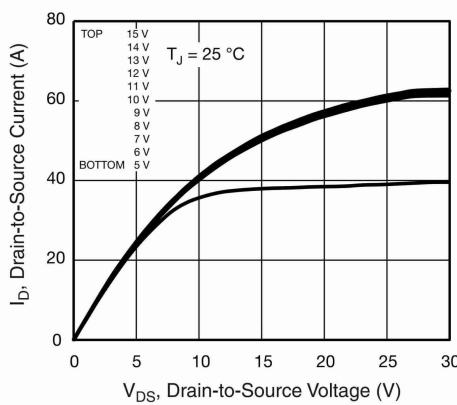
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	40	$^{\circ}\text{C}/\text{W}$
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.45	

SPECIFICATIONS ($T_J = 25^{\circ}\text{C}$, unless otherwise noted)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = 250 \mu\text{A}$		550	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 250 \mu\text{A}$		-	0.56	-	$^{\circ}\text{C}/\text{V}$
Gate-Source Threshold Voltage (N)	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		2	-	4	V
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 500 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	1	μA
		$V_{DS} = 400 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125^{\circ}\text{C}$		-	-	10	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 10 \text{ A}$	-	0.2	-	Ω
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 10 \text{ A}$		-	12	-	S
Dynamic							
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 100 \text{ V}$, $f = 1 \text{ MHz}$		-	3094	-	pF
Output Capacitance	C_{oss}			-	152	-	
Reverse Transfer Capacitance	C_{rss}			-	13	-	
Effective output capacitance, energy related ^a	$C_{o(er)}$	$V_{GS} = 0 \text{ V}$, $V_{DS} = 0 \text{ V to } 400 \text{ V}$		-	131	-	pF
Effective output capacitance, time related ^b	$C_{o(tr)}$			-	189	-	
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 10 \text{ A}$, $V_{DS} = 400 \text{ V}$	-	85	170	nC
Gate-Source Charge	Q_{gs}			-	14	-	
Gate-Drain Charge	Q_{gd}			-	28	-	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 400 \text{ V}$, $I_D = 10 \text{ A}$, $V_{GS} = 10 \text{ V}$, $R_g = 9.1 \Omega$		-	24	50	ns
Rise Time	t_r			-	31	62	
Turn-Off Delay Time	$t_{d(off)}$			-	117	176	
Fall Time	t_f			-	56	112	
Gate Input Resistance	R_g	$f = 1 \text{ MHz}$, open drain		-	1.8	-	Ω
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	20	A
Pulsed Diode Forward Current	I_{SM}			-	-	80	
Diode Forward Voltage	V_{SD}	$T_J = 25^{\circ}\text{C}$, $I_S = 10 \text{ A}$, $V_{GS} = 0 \text{ V}$		-	-	1.2	V
Reverse Recovery Time	t_{rr}	$T_J = 25^{\circ}\text{C}$, $I_F = I_S = 10 \text{ A}$, $dl/dt = 100 \text{ A}/\mu\text{s}$, $V_R = 20 \text{ V}$		-	437	-	ns
Reverse Recovery Charge	Q_{rr}			-	5.9	-	
Reverse Recovery Current	I_{RRM}			-	25	-	A

Notes

a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)


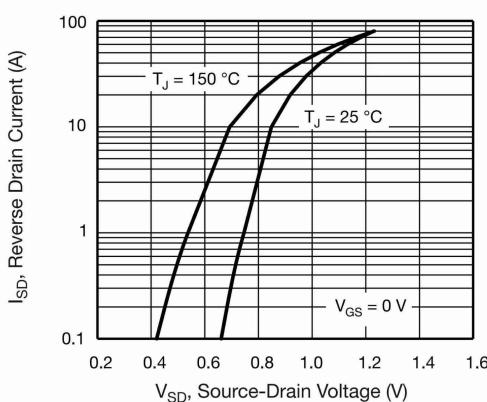


Fig. 7 - Typical Source-Drain Diode Forward Voltage

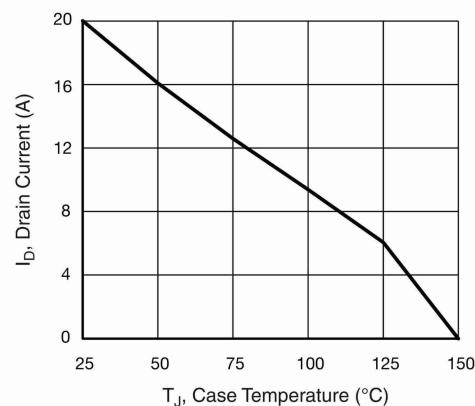


Fig. 9 - Maximum Drain Current vs. Case Temperature

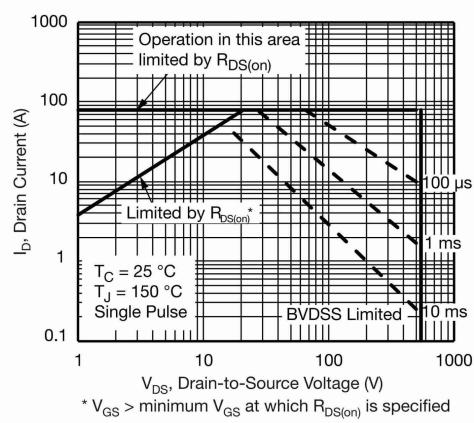


Fig. 8 - Maximum Safe Operating Area

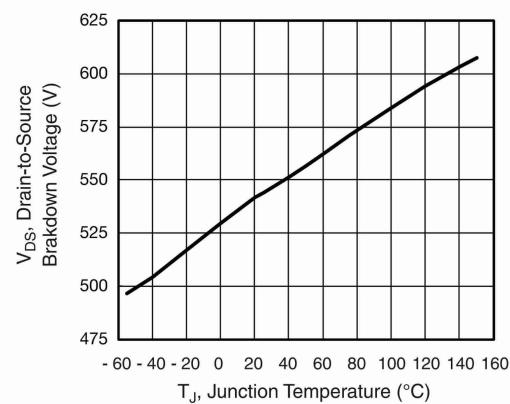


Fig. 10 - Temperature vs. Drain-to-Source Voltage

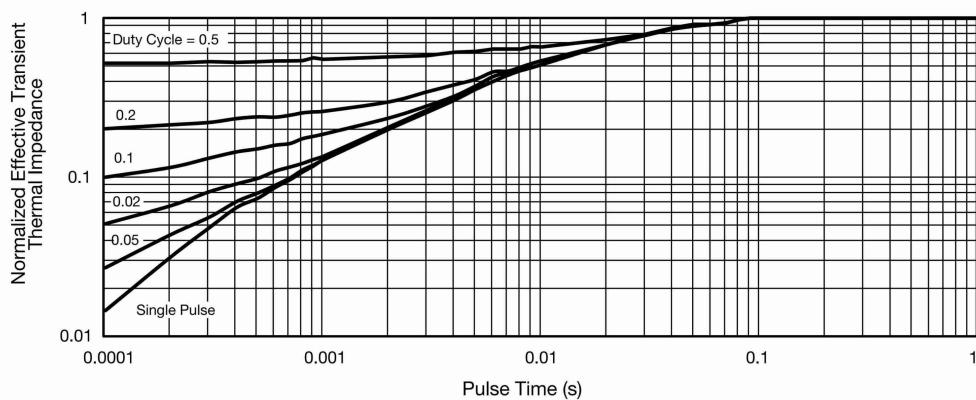


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case

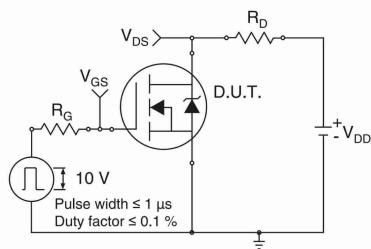


Fig. 12 - Switching Time Test Circuit

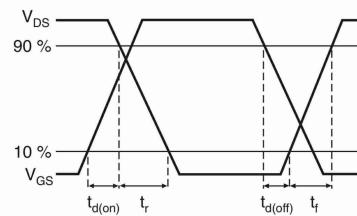


Fig. 13 - Switching Time Waveforms

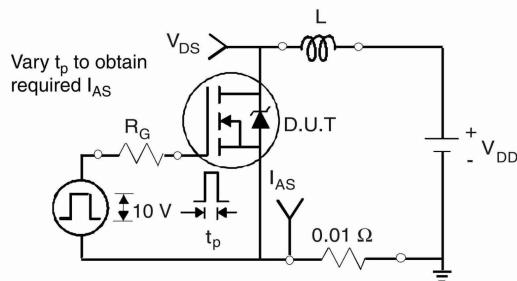


Fig. 14 - Unclamped Inductive Test Circuit

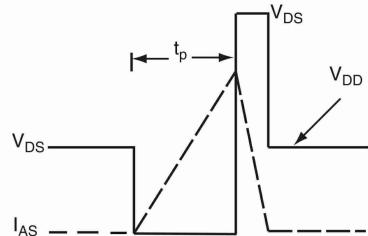


Fig. 15 - Unclamped Inductive Waveforms

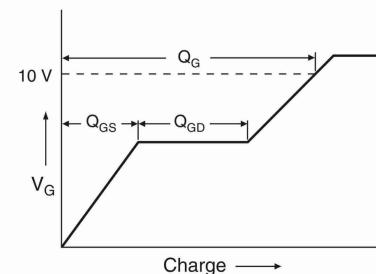


Fig. 16 - Basic Gate Charge Waveform

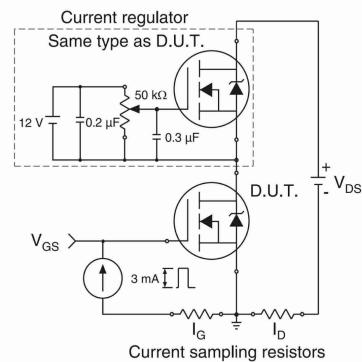
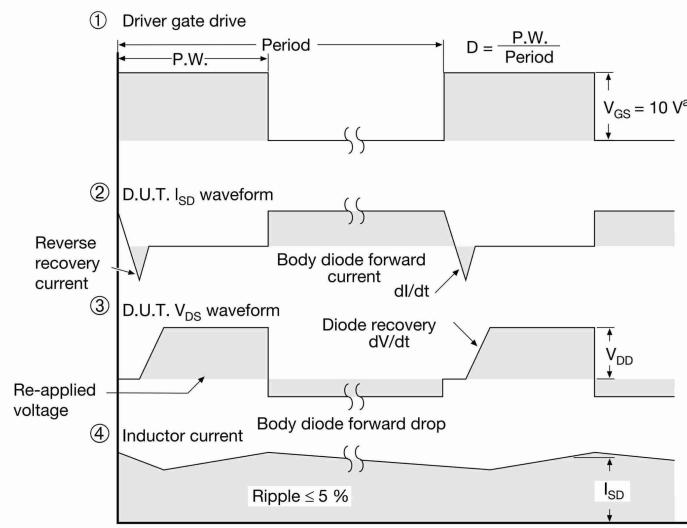
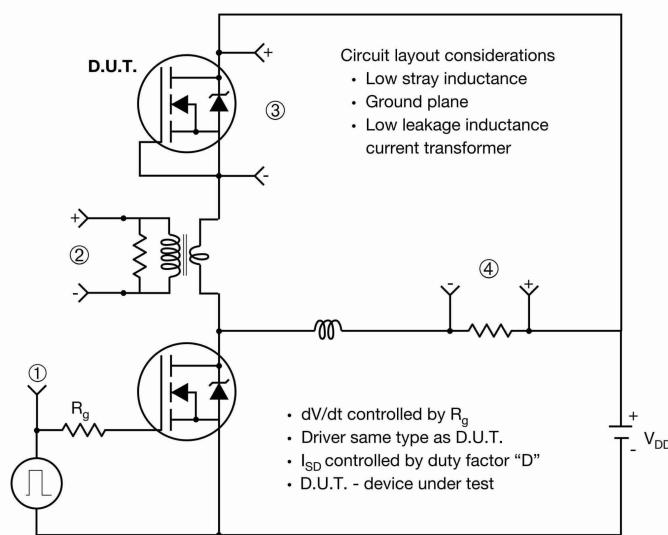
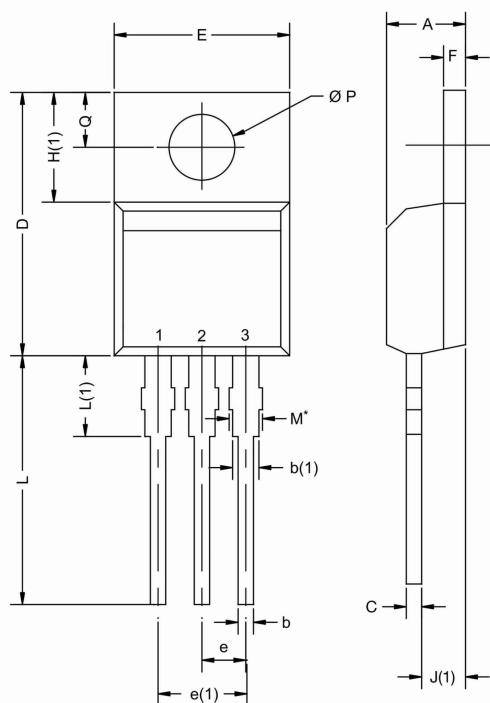


Fig. 17 - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit

Fig. 18 - For N-Channel

TO-220AB



DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.25	4.65	0.167	0.183
b	0.69	1.01	0.027	0.040
b(1)	1.20	1.73	0.047	0.068
c	0.36	0.61	0.014	0.024
D	14.85	15.49	0.585	0.610
E	10.04	10.51	0.395	0.414
e	2.41	2.67	0.095	0.105
e(1)	4.88	5.28	0.192	0.208
F	1.14	1.40	0.045	0.055
H(1)	6.09	6.48	0.240	0.255
J(1)	2.41	2.92	0.095	0.115
L	13.35	14.02	0.526	0.552
L(1)	3.32	3.82	0.131	0.150
Ø P	3.54	3.94	0.139	0.155
Q	2.60	3.00	0.102	0.118

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion)
Heatsink hole for HVM

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